

IC scanner type FLS 106 IC

Automatic spot-on RF analysis

The RF analysis of an integrated circuit or ASIC within an electronic module is always a challenge due to the narrow-spaced pins and signal leads. The FLS 106 IC scanner has been developed to enable such measurements as a surface scan with a measurement resolution of up to 50µm or a pin scan with the measuring points being spaced at less than 2 mm above any area of an electronic system. The scanner's long positioning distances of 600x400x125 mm let the user move the H- and E-field microprobes over the desired measuring object. The scan starting point is determined precisely with a video microscope. The near-field micro-probes can be moved automatically on all three axes over the chip surface and also rotated around the z axis. The FLS 106 IC scanner is controlled with the ChipScan scanner software via a PC. This software lets the user read out the measured data via a spectrum analyser, present this graphically in 2D or 3D as well as store and output this in a CSV file all at the same time. A software door towards the scanner control system allows measurements with an oscilloscope.

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